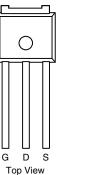
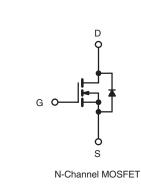
N-Channel 30-V (D-S) MOSFET

PRODUC	CT SUMMARY		
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)
30	0.0057 at V _{GS} = 10 V	40	13.8 nC
30	0.0076 at V_{GS} = 4.5 V	40	13.0110







FEATURES

- Halogen-free
- TrenchFET[®] Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- Low-Side Switch
- Notebook DC/DC



Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	30	v
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		40 ^a	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		40 ^a	
$Continuous Drain Current (1) = 150^{\circ} C)$	T _A = 25 °C		22.7 ^{b, c}	A
	T _A = 70 °C		19.7 ^{b, c}	
Pulsed Drain Current		I _{DM}	70	
Avalanche Current	L = 0.1 mH	I _{AS}	35	
Avalanche Energy	L = 0.1 mm	E _{AS}	61	mJ
Continuous Source Drain Diode Current	T _C = 25 °C	1-	40 ^a	Α
ntinuous Source-Drain Diode Current	T _A = 25 °C	I _S	4.1 ^{b, c}	A
	T _C = 25 °C		50	
Maximum Power Dissipation	T _C = 70 °C	P _D	32	w
	T _A = 25 °C		5 ^{b, c}	VV
	T _A = 70 °C		3.2 ^{b, c}	
Operating Junction and Storage Temperature	e Range	T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Tempera	ature) ^{d, e}	, , , , , , , , , , , , , , , , , , ,	260	

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	20	25	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	2.0	2.5	0/11

Notes:

a. Based on $T_C = 25$ °C. Package limited. b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static			1		1 1	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			27		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.5		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1		3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			5	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	50			Α
		$V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		0.0047	0.0057	-
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 18 A		0.0062	0.0076	Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		90		S
Dynamic ^b						
Input Capacitance	C _{iss}			1720		
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$		355		pF
Reverse Transfer Capacitance	C _{rss}			130		
Tabal Oaks Observe	0	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		29	44	
Total Gate Charge	Qg			13.8	21	-0
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$		5.0		nC
Gate-Drain Charge	Q _{gd}			4.6		
Gate Resistance	R _g	f = 1 MHz		1.1	2.2	Ω
Turn-On Delay Time	t _{d(on)}			25	40	
Rise Time	t _r	V_{DD} = 15 V, R_L = 15 Ω		14	25	
Turn-Off Delay Time	t _{d(off)}	$\rm I_D \cong 1.0$ A, $\rm V_{GEN}$ = 4.5 V, $\rm R_g$ = 1 Ω		30	45	
Fall Time	t _f			15	25	
Turn-On Delay Time	t _{d(on)}			11	20	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 15 Ω		9	15	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 1.0 A, V_{GEN} = 10 V, R_g = 1 Ω		27	40	
Fall Time	t _f			9	15	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	۱ _S	$T_{C} = 25 \ ^{\circ}C$			40	Δ
Pulse Diode Forward Current	I _{SM}				70	A
Body Diode Voltage	V _{SD}	$I_{S} = 4.1 \text{ A}, V_{GS} = 0 \text{ V}$		0.75	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			25	50	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 4.1 A, dl/dt = 100 A/μs, T _J = 25 °C		17	35	nC
Reverse Recovery Fall Time	t _a	$r_F = 4.1 \text{ A}, \text{ u/ul} = 100 \text{ A/}\mu\text{s}, \text{I}_J = 25 ^{\circ}\text{C}$		13		
Reverse Recovery Rise Time	t _b			12		ns

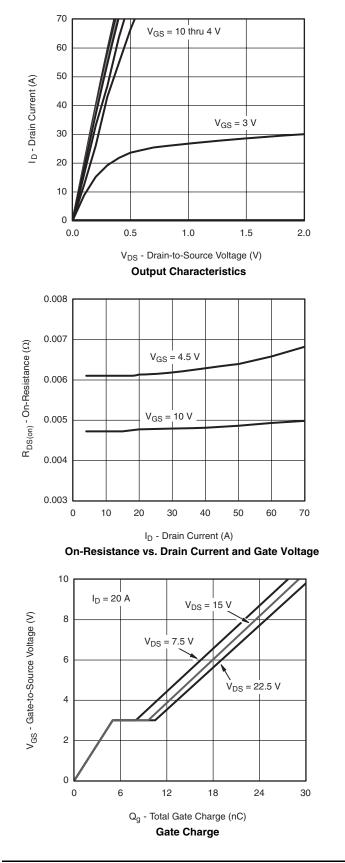
Notes:

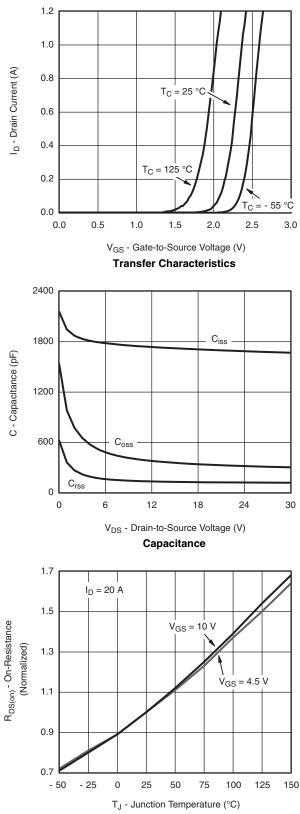
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



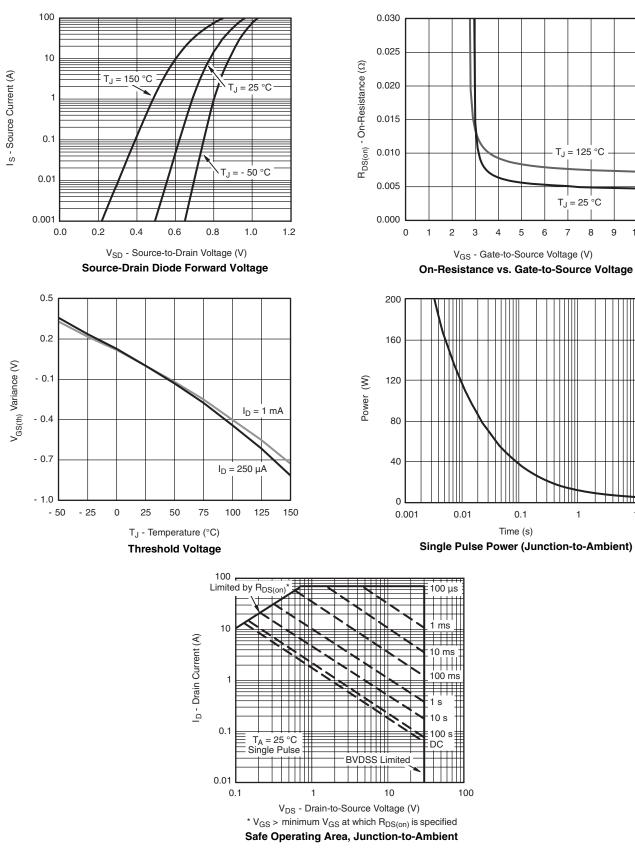


On-Resistance vs. Junction Temperature

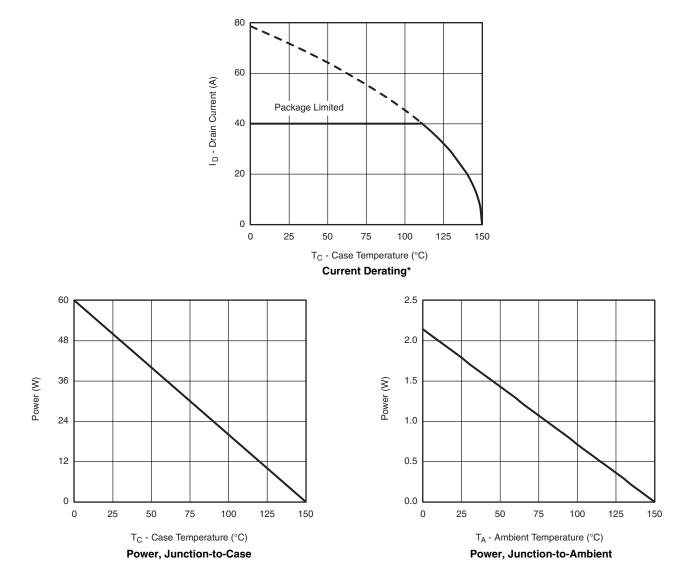
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10

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

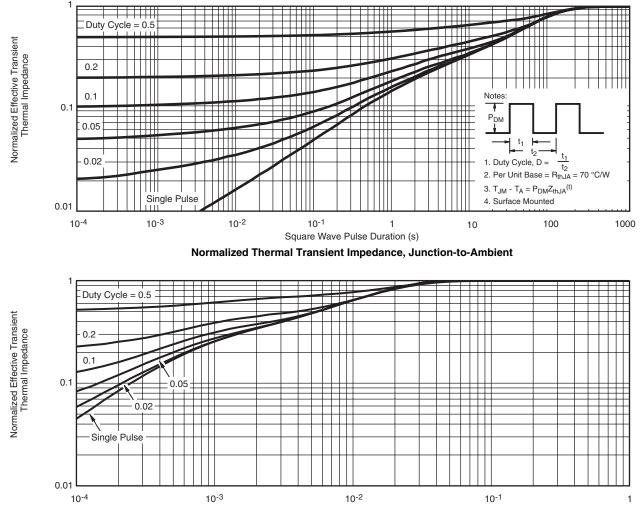


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

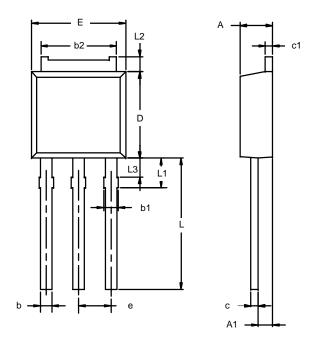


Square Wave Pulse Duration (s)

Normalized Thermal Transient Impedance, Junction-to-Case

Din-Tek

TO-251AA (DPAK)



Note: Dimension L3 is for reference only.

Ain 1.21 0.89 0.71 0.76 0.23 0.46 0.46 0.97	Max 2.38 1.14 0.89 1.14 5.43 0.58 0.58 6.22	Min 0.087 0.035 0.028 0.030 0.206 0.018 0.018	Max 0.094 0.045 0.035 0.045 0.045 0.045 0.023
0.89 0.71 0.76 0.23 0.46 0.46	1.14 0.89 1.14 5.43 0.58 0.58	0.035 0.028 0.030 0.206 0.018	0.045 0.035 0.045 0.214 0.023
0.71 0.76 0.23 0.46 0.46	0.89 1.14 5.43 0.58 0.58	0.028 0.030 0.206 0.018	0.035 0.045 0.214 0.023
0.76 5.23 0.46 0.46	1.14 5.43 0.58 0.58	0.030 0.206 0.018	0.045 0.214 0.023
5.23 0.46 0.46	5.43 0.58 0.58	0.206	0.214
.46 .46	0.58 0.58	0.018	0.023
.46	0.58		
		0.018	0.023
.97	6.22		
	0.22	0.235	0.245
5.48	6.73	0.255	0.265
2.28	BSC	0.090	BSC
.89	9.53	0.350	0.375
.91	2.28	0.075	0.090
.89	1.27	0.035	0.050
.15	1.52	0.045	0.060
)	.91 .89 .15	.15 1.27	1.27 0.035

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